Issue Classification	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10601158	BARDZIL ET AL.
	Examiner	Art Unit
	Nano, Sargon N	2157

ORIGINAL		INTERNATIONAL CLASSIFICATION									
CLASS	SUBCLASS	CLAIMED					NON-CLAIMED				
709	248	G	0	6	F	15 / 16 (2006.01.01)	G	0	6	F	15 / 173 (2006.01.01)

CROSS REFERENCE(S)

CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)					
709	238	241				

Nano, Sargon N	11/20/07		Total Claims Allowed:
(Assistant Examiner)	(Date)	ARIO ETIENNE · 11/27/07	37
		SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2100	

(Legal Instruments Examiner)	(Date)	(Primary Examiner)	(Date)	O.G. Print Claim(s)	O.G. Print Figure
				42	3 A

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